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SHEET 1 OF 1
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FORM PTO - 1449 INFORMATION DISCLOSURE STATEMENT				ATTORNEY DOCKET NO.: MLB-068 APPLICANTS: Jacobson et al. SERIAL NO.: 09/590,044 FILING DATE: June 8, 2000 GROUP: 2823						
U.S. PATENT DOCUMENTS										
EXAM. INIT.		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE			
FOREIGN PATENT DOCUMENTS										
EXAM. INIT.		DOCUMENT NUMBER	DATE	COUNTRY CODE	CLASS	SUB CLASS	FILING DATE	ABSTRACT ONLY	ENGLISH LANG (Y/N)	
OTHER ART, JOURNAL ARTICLES, ETC.										
EXAM. INIT.	OTHER DOCUMENTS: (Including Author, Title, Date, Relevant Pages, Place of Publication)									
NB	C1	Keller et al., "A Chemical Method for Introducing Haptens onto DNA Probes," <u>Analytical Biochemistry</u> , Volume 170, 1988, pp. 441-450.								
NB	C2	Steigerwald et al., "Surface Derivatization and Isolation of Semiconductor Cluster Molecules," <u>Journal of the American Chemical Society</u> , Volume 110, No. 10, May 11, 1988, pp. 3046-3050.								
NB	C3	Jarvis et al., "Solution Synthesis and Photoluminescence Studies of Small Crystallites of Cadmium Telluride," <u>Materials Research Society Symposium Proceedings</u> , Volume 272, April 1992, pp. 229-234.								
NB	C4	Murray et al., "Synthesis and Characterization of Nearly Monodisperse CdE (E=S, Se, Te) Semiconductor Nanocrystallinities," <u>Journal of the American Chemical Society</u> , Volume 115, 1993, pp. 8706-8715.								
NB	C5	Dabbouoi et al., "Langmuir-Blodgett Manipulation of Size-Selected CdSe Nanocrystallinities," <u>Chemistry of Materials</u> , Volume 6, No. 2, February 1994, pp. 216-219.								
NB	C6	Heath et al., "Pressure/Temperature Phase Diagrams and Superlattices of Organically Functionalized Metal Nanocrystal Monolayers: The Influence of Particle Size, Size Distribution, and Surface Passivant," <u>Journal of Physical Chemistry B</u> , Volume 101, No. 2, January 9, 1997, pp. 189-197.								
NB	C7	Alivisatos, "Electrical Studies of Semiconductor-Nanocrystal Colloids," <u>MRS Bulletin</u> , Volume 23, No. 2, ISSN: 0883-7694, February 1998, pp. 18-23.								
EXAMINER		Neal Berezny				DATE CONSIDERED				10-15-02